



UNI-SEMICONDUCTOR CO., LTD

宇力半导体有限公司



AP15N10K Data Sheet

V 1.1

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100V N-CHANNEL ENHANCEMENT MODE POWER MOSFET

Features

- 100V, 14.6A
- $R_{DS(ON)} = 100\text{m}\Omega$ (max.) @ $V_{GS} = 10\text{V}$, $I_D = 5\text{A}$
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology
- RoHS Compliant & Halogen-Free

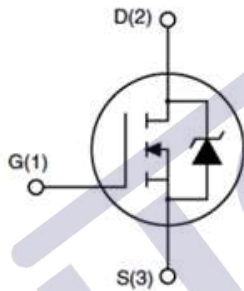
Application

- Synchronous buck converter applications.

Package



TO-252



Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Max.	Units
V_{DS}	Drain-Source Voltage	100	V
V_{GS}	Gate-Source Voltage	± 20	V
I_D	Continuous Drain Current, $V_{GS} @ 10\text{V}$ <small>note1,6</small>	$T_C = 25^\circ\text{C}$	14.6
		$T_C = 100^\circ\text{C}$	10
I_{DM}	Pulsed Drain Current <small>note2</small>	25	A
P_D	Power Dissipation <small>note4</small>	$T_C = 25^\circ\text{C}$	30
E_{AS}	Single Pulsed Avalanche Energy <small>note3</small>	0.8	mJ
$R_{\theta JA}$	Thermal Resistance, Junction to Case <small>note1</small>	3	$^\circ\text{C}/\text{W}$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$

Electrical Characteristics $T_C=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	100	-	-	V
I_{DSS}	Drain-Source Leakage Current	$V_{DS} = 80V, V_{GS} = 0V$	-	-	10	μA
		$V_{DS} = 80V, T_C = 55^\circ\text{C}$	-	-	100	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	± 100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.2	-	2.9	V
$R_{DS(on)}$	Static Drain-Source On-Resistance ^{note2}	$V_{GS} = 10V, I_D = 5A$	-	85	100	m Ω
		$V_{GS} = 4.5V, I_D = 3A$	-	90	110	m Ω
g_{FS}	Forward Transconductance	$V_{DS} = 5V, I_D = 5A$	-	14	-	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$ $f = 1.0\text{MHz}$	-	450	-	pF
C_{oss}	Output Capacitance		-	55	-	pF
C_{riss}	Reverse Transfer Capacitance		-	16	-	pF
Q_g	Total Gate Charge	$V_{DS} = 50V, I_D = 5A,$ $V_{GS} = 10V$	-	11.9	-	nC
Q_{gs}	Gate-Source Charge		-	2.8	-	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	1.7	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 50V, I_D = 5A,$ $R_G = 3.3\Omega, V_{GS} = 10V$	-	3.8	-	ns
t_r	Turn-On Rise Time		-	25.8	-	ns
$t_{d(off)}$	Turn-Off Delay Time		-	16	-	ns
t_f	Turn-Off Fall Time		-	8.8	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain to Source Diode Forward Current ^{note1,5}		-	-	14.6	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current ^{note2,5}		-	-	25	A
V_{SD} ^{note2}	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_S = 1A$	-	-	1.2	V

Note :

- The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- The EAS data shows Max. rating . The test condition is $V_{DD}=25V, V_{GS}=10V, L=0.1mH, I_{AS}=50A$
- The power dissipation is limited by 150°C junction temperature
- The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.
- Package limitation current is 85A

Typical Performance Characteristics

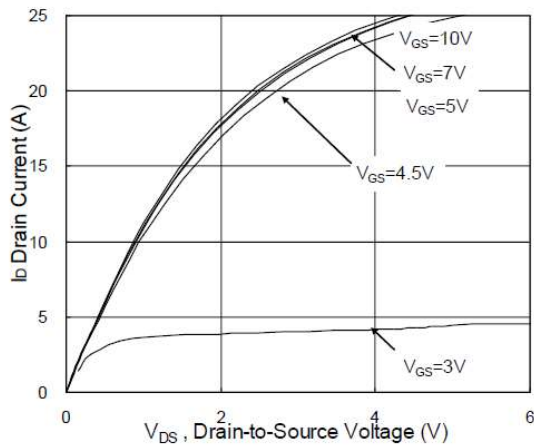


Figure 1. Output Characteristics

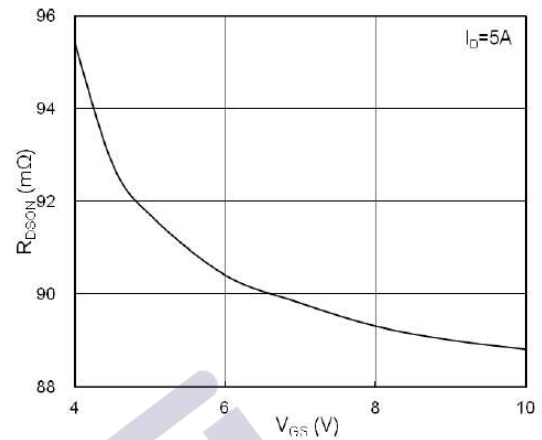


Figure 2. On Resistance vs. Gate-Source Voltage

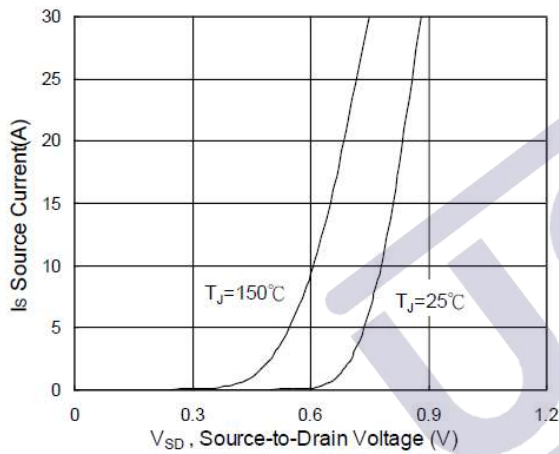


Figure 3. Body Diode Forward Voltage vs. Source Current and Temperature

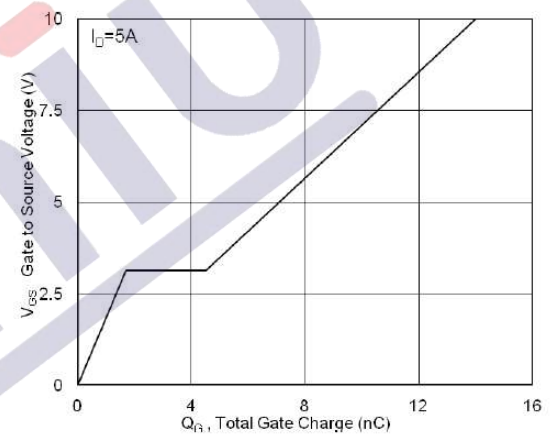


Figure 4. Gate Charge Characteristics

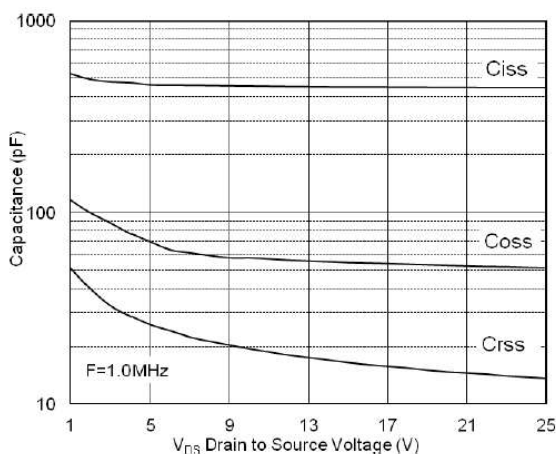


Figure 5. Capacitance Characteristics

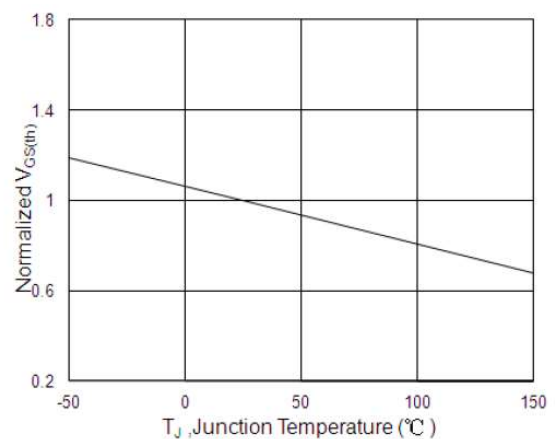


Figure 6. Normalized Threshold Voltage vs. Junction Temperature

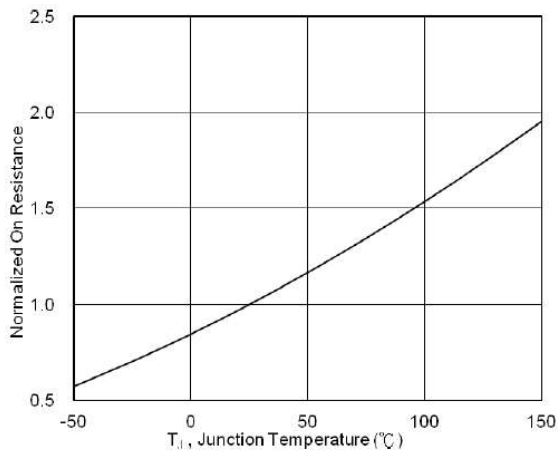


Figure 7. N Normalized On Resistance vs. Junction Temperature

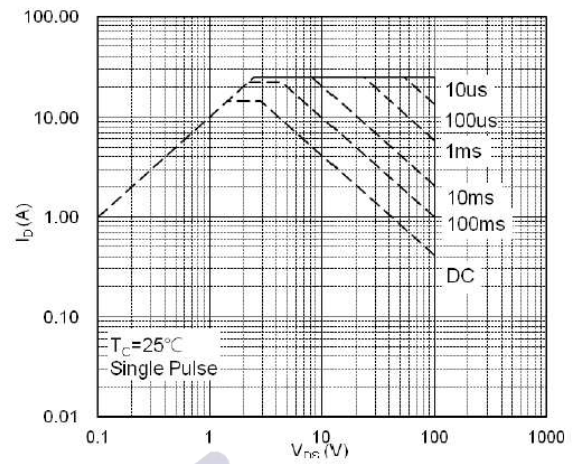


Figure 8. Maximum Safe Operating Area

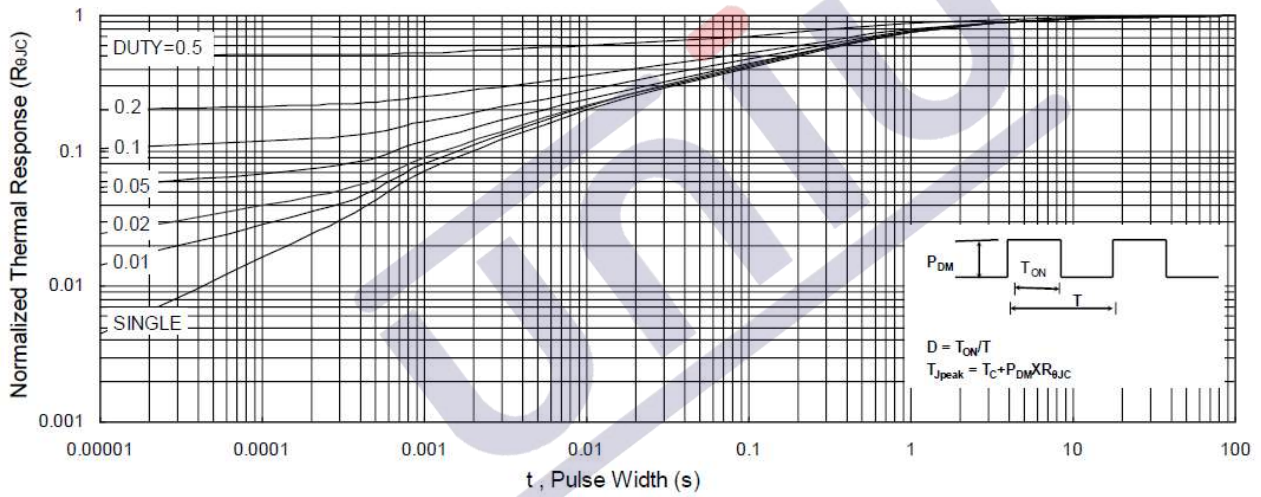


Figure 9. Effective Transient Thermal Impedance

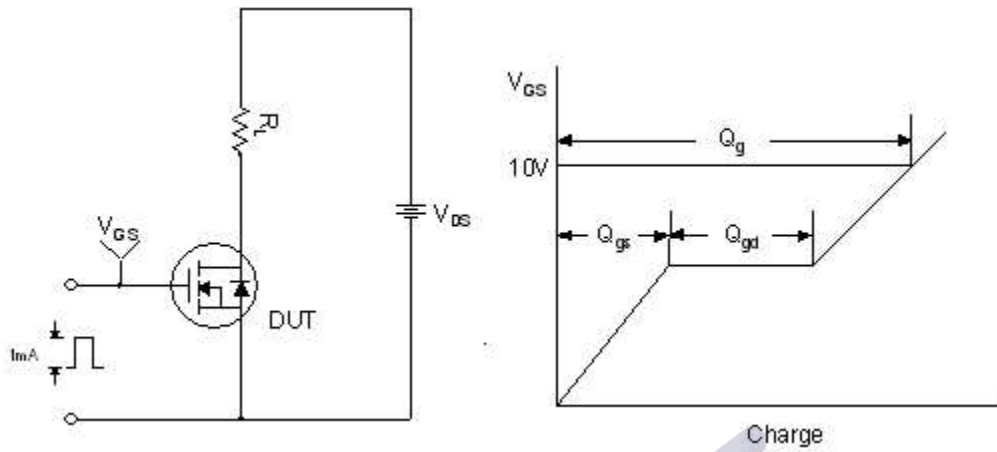


Figure 10. Gate Charge Test Circuit & Waveform

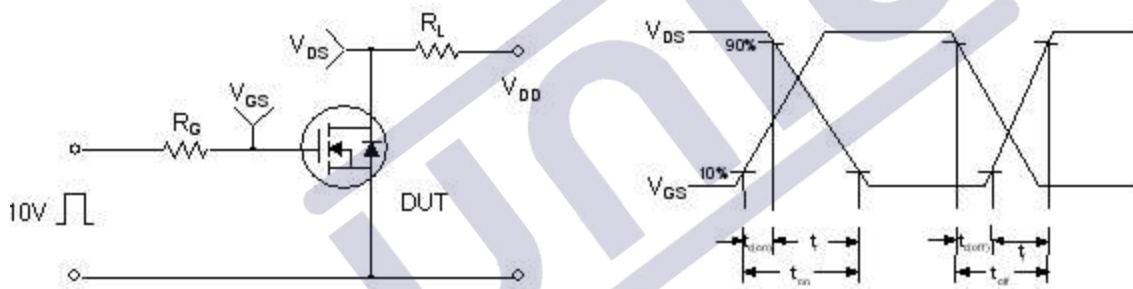


Figure 11. Resistive Switching Test Circuit & Waveforms

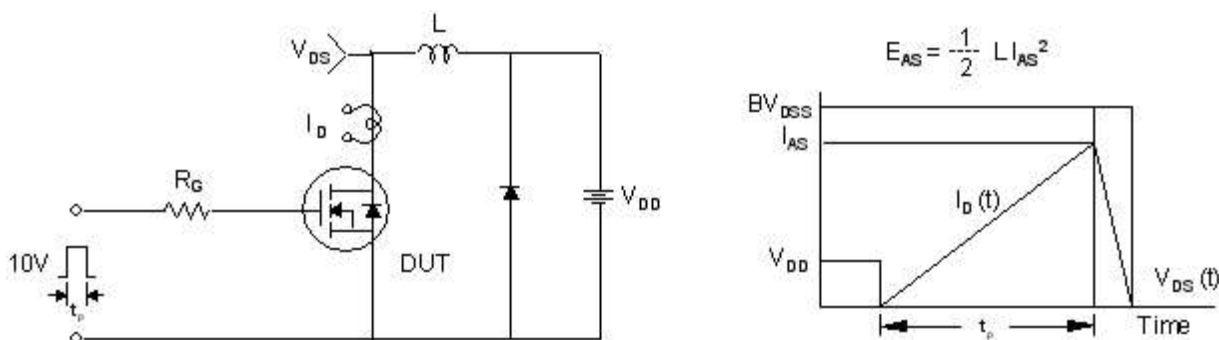
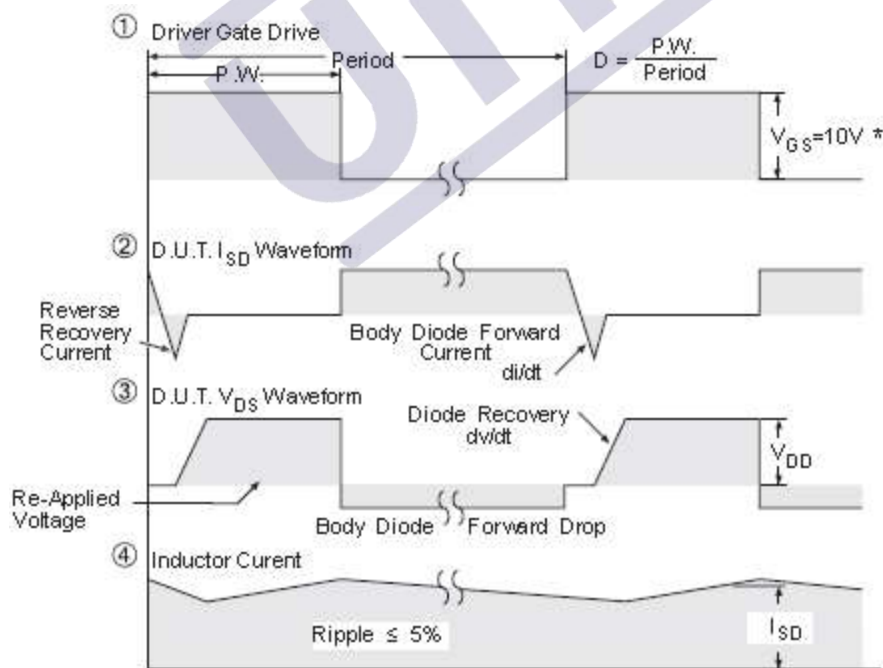
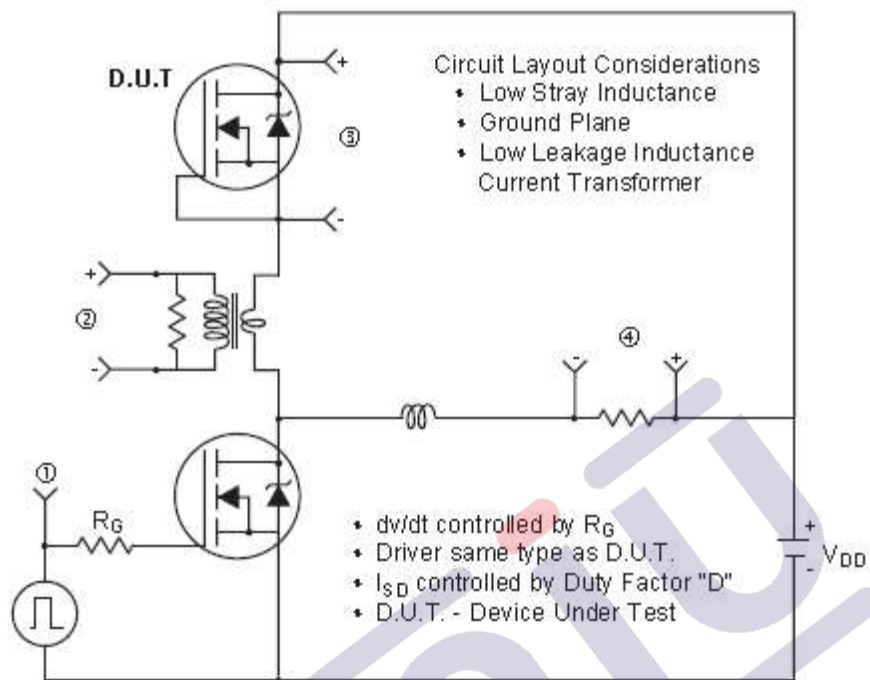


Figure 12. Unclamped Inductive Switching Test Circuit & Waveforms



* $V_{GS} = 5V$ for Logic Level Devices

Figure 13. Peak Diode Recovery dv/dt Test Circuit & Waveforms (For N-channel)

1.版本记录

DATE	REV.	DESCRIPTION
2018/04/19	1.0	First Release
2021/11/12	1.1	Layout adjustment

2.免责声明

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